

<b>Notice of References Cited</b>	Application/Control No. 10/016,562	Applicant(s)/Patent Under Reexamination HSIEH ET AL.	
	Examiner DuyVu n Deo	Art Unit 1765	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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